

## DC/AC ELECTRICAL CHARACTERIZATION FACILITY (Pulse Generator)



**MODEL:** HP 8110A 150 MHz pulse generator

**INSTALLATION PLACE:** DC Electrical Characterization Laboratory (room No14 new-building), Department of Microelectronics

### **DESCRIPTION:**

The HP 81110A generate all the standard pulses and digital patterns needed to test current logic technologies (CMOS, TTL, LVDS, ECL, etc.). With the optional second channel, multi-level and multi-timing signals up to 60 MHz can be obtained using the internal channel addition feature.

### **SPECIFICATIONS**

1. Signal type: Single or dual channel pulse pattern generator
2. Data Capabilities: 150 Mb/s, RZ/NRZ, 4 kb data with variable pulse parameters
3. BNC outputs
4. Timing Characteristics:
  - Frequency range: 1 MHz to 150 MHz
  - Timing resolution 3 digits, 10 ps best case
  - Period range: 6.65 ns to 999 ms
  - Width range: 3.30 ns to (period - 3.3 ns), maximum 999 ms
  - Double pulse delay range: (width + 1.5 ns) to (period - width - 1.5 ns)
  - Transition time range (10/90): 2.00 ns to 200 ms variable
  - Accuracy:  $\pm 5\% \pm 250$  ps
  - Pulse height:  $\pm 10$  Volts

### **APPLICATIONS**

1. Real World Pulses
2. Pattern Based Timing
3. Clean pulses
4. Application in Pulsed measurements
5. Memory testing

### **CERTIFICATION/ACCREDITATION**

The facility is not certified or accredited.

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